

## ABSTRACT OF THE DISCLOSURE

The present invention concerns a microscope, in particular a confocal or double confocal scanning microscope, as well as a method for operating a microscope, at least one specimen support unit associated with the specimen being provided, at least one reference specimen of known configuration being provided, and the reference specimen being detectable by light microscopy for calibration, alignment or adjustment of the microscope. With the microscope according to the present invention and the method according to the invention for operating a microscope, drift-related changes can be detected and compensated for. Auxiliary means with which a specimen can easily and reliably be focused are also provided.

(FIG. 7)